

June 2014

# FQP3N80C / FQPF3N80C N-Channel QFET® MOSFET 800 V, 3.0 A, 4.8 $\Omega$

#### **Features**

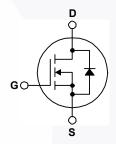
- 3.0 A, 800 V,  $R_{DS(on)}$  = 4.8  $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_D$  = 1.5 A
- Low Gate Charge (Typ. 13 nC)
- Low Crss (Typ. 5.5 pF)
- · 100% Avalanche Tested

## **Description**

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.







## MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter			FQP3N80C	FQPF3N80C	Unit
V <sub>DSS</sub>	Drain to Source Voltage		800		V	
I <sub>D</sub>	Drain Current	-Continuous (T <sub>C</sub> = 25°C)	-Continuous (T <sub>C</sub> = 25°C)		3 *	Α
	Diain Current	-Continuous (T <sub>C</sub> = 100°C)	-Continuous (T <sub>C</sub> = 100°C)		1.9 *	Α
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	12	12 *	Α
V <sub>GSS</sub>	Gate to Source Voltage			± 30		V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2		(Note 2)	320		mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	3		Α
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	10.7		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5		V/ns	
$P_{D}$	Power Dissipation	(T <sub>C</sub> = 25°C)		107	39	W
	Power Dissipation	- Derate above 25°C		0.85	0.31	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150		°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300		°C

<sup>\*</sup>Drain current limited by maximum junction temperature.

#### Thermal Characteristics

Symbol	Parameter	FQP3N80C	FQPF3N80C	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	1.17	3.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max	62.5	62.5	°C/W

## **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQP3N80C	FQP3N80C	TO-220	Tube	Tube	N/A	50 units
FQPF3N80C	FQPF3N80C	TO-220F	Tube	Tube	N/A	50 units

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	800			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		1		V/°C
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V			10	μΑ
I <sub>DSS</sub>		V <sub>DS</sub> = 640 V, T <sub>C</sub> = 125°C			100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V	-		100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1.5 A	-	4.0	4.8	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 1.5 A		3		S
•	ic Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		543	705	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		54	70	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			5.5	7.5	pF
Switchi	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time V <sub>DD</sub> = 400 V, I <sub>D</sub> = 3 A,			15	40	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		43.5	95	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			22.5	55	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)		32	75	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 640 V, I <sub>D</sub> = 3 A,	/	13	16.5	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		3.4		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4)		5.8		nC
Drain-S	Source Diode Characteristics and	I Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode			3.0	Α	
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode For			12	Α	
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 3.0 A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 3.0 A,		642		ns
Q <sub>rr</sub>	Reverse Recovery Charge $dI_F / dt = 100 \text{ A/}\mu\text{s}$			4.0		μС

#### Notes

<sup>1.</sup> Repetitive Rating : Pulse width limited by maximum junction temperature.

<sup>2.</sup> L = 67 mH, I<sub>AS</sub> = 3.0 A, V<sub>DD</sub> = 50 V, R<sub>G</sub> = 25  $\Omega$ , starting T<sub>J</sub> = 25°C.

 $<sup>3.~</sup>I_{SD} \leq 3~A,~di/dt \leq 200~A/\mu s,~V_{DD} \leq BV_{DSS,}~starting~~T_J = 25^{\circ}C.$ 

<sup>4.</sup> Essentially independent of operating temperature.

## **Typical Characteristics**

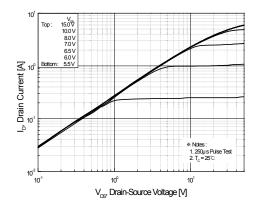


Figure 1. On-Region Characteristics

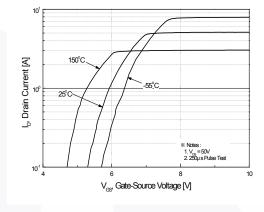


Figure 2. Transfer Characteristics

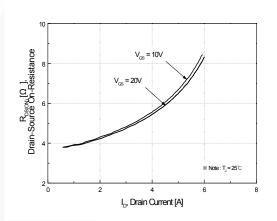


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

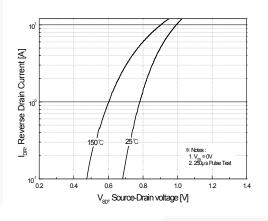


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

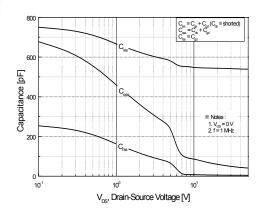


Figure 5. Capacitance Characteristics

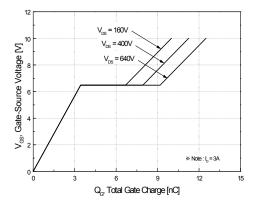


Figure 6. Gate Charge Characteristics

## Typical Characteristics (Continued)

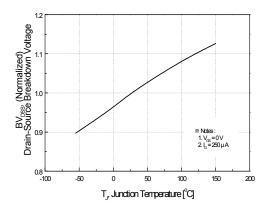


Figure 7. Breakdown Voltage Variation vs Temperature

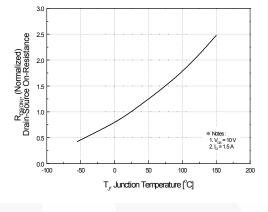


Figure 8. On-Resistance Variation vs Temperature

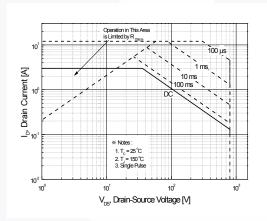


Figure 9-1. Maximum Safe Operating Area for FQP3N80C

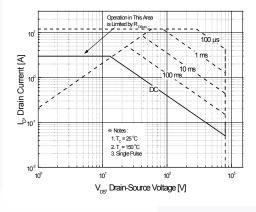


Figure 9-2. Maximum Safe Operating Area for FQPF3N80C

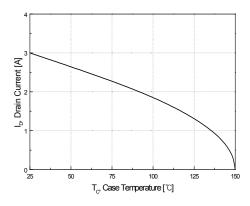


Figure 10. Maximum Drain Current vs Case Temperature

## **Typical Characteristics** (Continued)

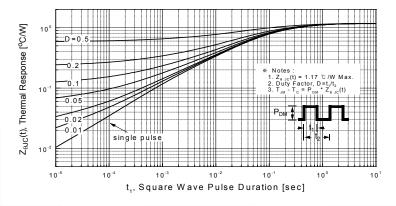


Figure 11-1. Transient Thermal Response Curve for FQP3N80C

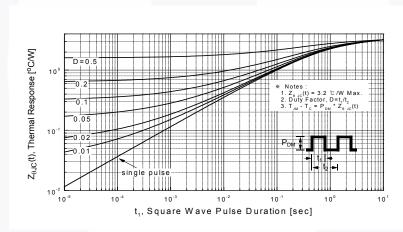


Figure 11-2. Transient Thermal Response Curve for FQPF3N80C

Figure 12. Gate Charge Test Circuit & Waveform

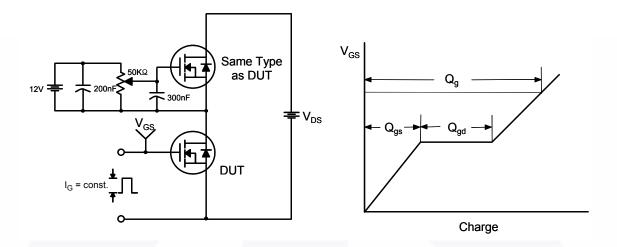


Figure 13. Resistive Switching Test Circuit & Waveforms

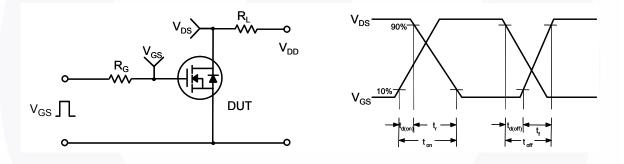
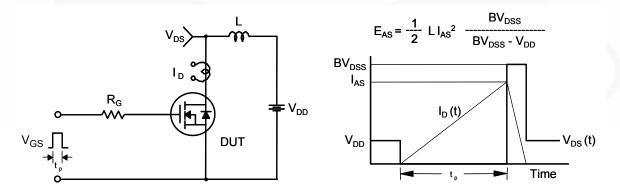


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



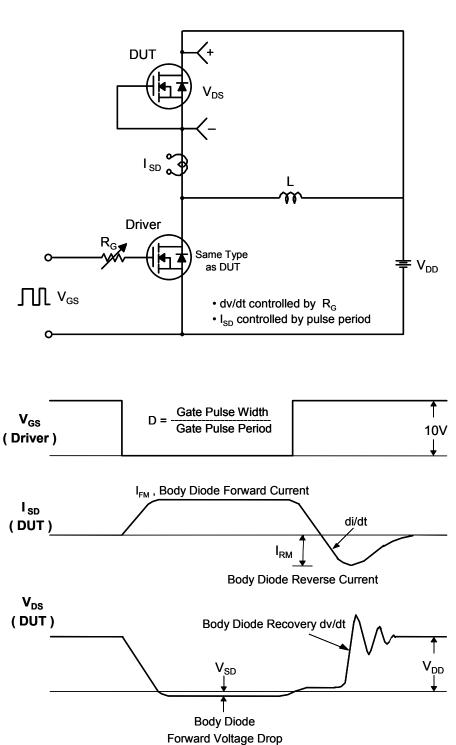


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

### **Mechanical Dimensions**

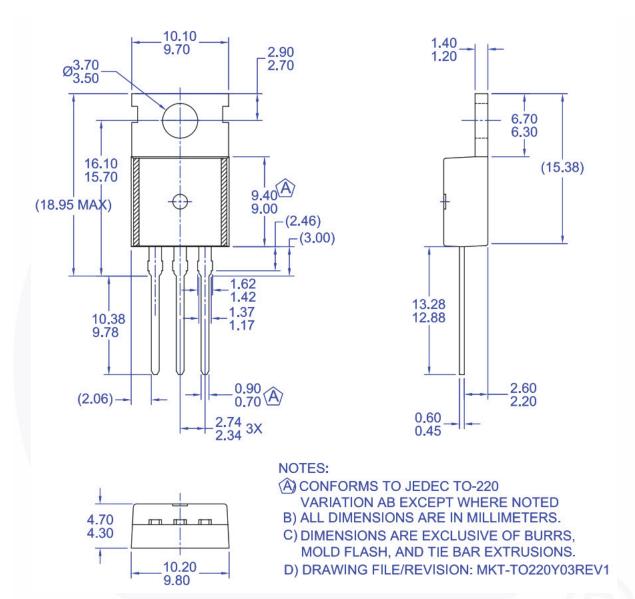


Figure 16. TO220, Molded, 3-Lead, Jedec Variation AB

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### **Mechanical Dimensions**

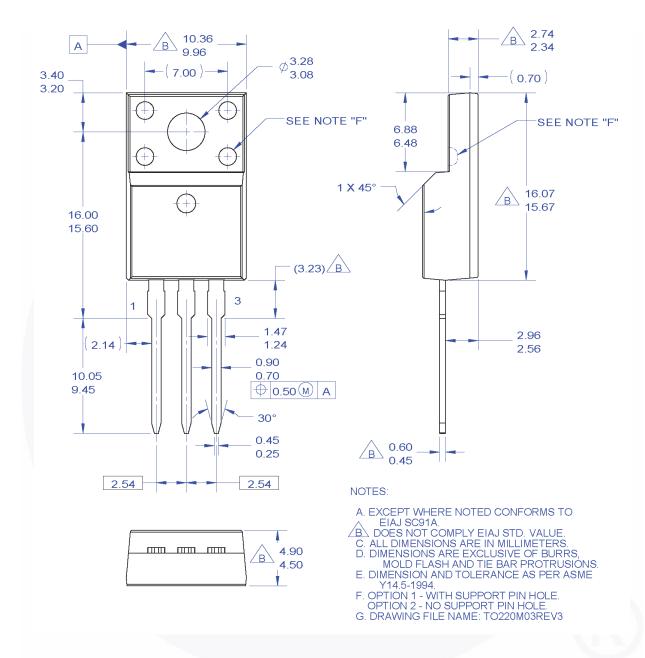


Figure 17. TO220, Molded, 3-Lead, Full Pack, EIAJ SC91, Straight Lead

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